

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	1	("5538924").PN.	USPAT	OR	OFF	2005/03/16 16:01
L5	1	4 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 16:07
L6	1	("6180261").PN.	USPAT	OR	OFF	2005/03/16 16:07
L7	1	6 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 16:20
L8	1	("6653710").PN.	USPAT	OR	OFF	2005/03/16 16:20
L9	1	7 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 16:20
L10	1	8 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 16:50
L11	2595	257/678	USPAT	OR	ON	2005/03/16 16:51
L12	1525	257/701	USPAT	OR	ON	2005/03/16 16:51
L13	2395	257/777	USPAT	OR	ON	2005/03/16 16:51
L14	3883	257/778	USPAT	OR	ON	2005/03/16 16:51
L15	900	257/782	USPAT	OR	ON	2005/03/16 16:51
S220	4	(stress adj relief adj element) and die	USPAT	OR	ON	2005/03/16 14:25

S22 1	0	(stress adj relief adj element) and die and (crack adj2 element)	USPAT	OR	ON	2005/03/16 14:26
S22 2	23	die and (crack adj2 element)	USPAT	OR	ON	2005/03/16 14:26
S22 3	2	die and (crack adj2 element) and stress and dielectric	USPAT	OR	ON	2005/03/16 14:29
S22 4	1	"6248857".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:28
S22 5	1	"6180261".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:28
S22 6	1	"6121406".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:28
S22 7	1	"6107448".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:29
S22 8	1	"6090906".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:29
S23 0	2	S223 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 14:33
S23 1	1	S225 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 14:42
S23 2	1	S228 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 14:45
S23 3	11	(low adj k-dielectric)	USPAT	OR	ON	2005/03/16 14:44
S23 4	2	(low adj k-dielectric) and stress and crack	USPAT	OR	ON	2005/03/16 14:45
S23 5	1	("6653710").PN.	USPAT	OR	OFF	2005/03/16 14:45

S23 6	1	("6492484").PN.	USPAT	OR	OFF	2005/03/16 14:45
S23 7	1	S235 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 14:50
S23 8	1	"6451681".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:46
S23 9	1	"5851903".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:47
S24 0	1	"5538924".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:47
S24 1	1	S240 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 14:49
S24 2	1	S236 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 14:49
S24 3	1	"5095297".PN.	USPAT; USOCR	OR	ON	2005/03/16 14:50
S24 4	1	S243 and (stress or relief or element or scribe or monitor or line or lane or low or k-dielectric or dielectric or dummy or vias or aperture or function or circuit or circuitry or circumference or surrounding o r surround or area or semiconductor or metal or crack or stop or main or die or chip)	USPAT	OR	ON	2005/03/16 16:01